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	NOTE : OLDIL
LABORATORY LOCATION/	NSF Engineering Sdn. Bhd.
CENTRAL OFFICE:	PLO 819A, Jalan Platinum 4, Platinum Business Park, Kawasan
	Perindustrian Pasir Gudang, Zon 12B, 81700 Pasir Gudang, Johor,
	81700,
	JOHOR
	MALAYSIA
ACCREDITED SINCE :	06 APRIL 2025
FIELD(S) OF TESTING:	MECHANICAL
FIELD(S) OF CALIBRATION:	ELECTRICAL
	PRESSURE
	TEMPERATURE

This laboratory has demonstrated its technical competence to operate in accordance with MS ISO/IEC 17025:2017 (ISO/IEC 17025:2017).

This laboratory's fulfillment of the requirements of ISO/IEC 17025 means the laboratory meets both the technical competence requirements and management system requirements that are necessary for it to consistently deliver technically valid test results and calibrations. The management system requirements in ISO/IEC 17025 are written in language relevant to laboratory operations and operate generally in accordance with the principles of ISO 9001 (see Joint ISO-ILAC-IAF Communiqué dated April 2017).

* The uncertainty covered by the CMC is expressed as the expanded uncertainty corresponding to a coverage probability of approximately 95 % and have a coverage factor of k=2 unless stated otherwise.

	PLO 819A, Jalan Platinum 4, Platinum Business Park, Kawasan Perindustrian Pasir Gudang, Zon 12B, 81700 Pasir Gudang, Johor , 81700, Johor
FIELD(S) OF TESTING:	MECHANICAL,

SCOPE OF TESTING: MECHANICAL

Measurement	Material / Product Tested	Type Of Test / Properties Measured / Range Of Measurement	Standard Test Methods / Equipment / Techniques	
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FIELD(S) OF CALIBRATION: ELECTRICAL, PRESSURE, HEAT & TEMPERATURE

SCOPE OF CALIBRATION: ELECTRICAL

Instrument	Range	Calibration and	Remarks
Calibrated/Measurement		Measurement	
Parameter		Capability	
		Expressed as an	
		Uncertainty (±)*	
Measuring Instruments (dc	0 mV to 330 mV	22 mV/V + 1.6 mV	Generate using Fluke
Voltage)	330 mV to 3.3 V	14 mV/V + 1.8 mV	5522A based on
	3.3 V to 33 V	14 mV/V + 48 mV	EURAMET cg-15,
	33 V to 330 V	23 mV/V + 23 mV	Version 3 (02/2015)
	330 V to 1000 V	21 mV/V + 2.2 mV	
		Note:	
		Apply EOS for on-	
		site	
Measuring Instrument (ac Voltage)	33 mV to 750 V	See Matrix D	Generate using Fluke
3 11 1 (11 1 11 11 11 11 11 11 11 11 11 1			5522A based on
		Note:	EURAMET cg-15,
		Apply EOS for on-	Version 3 (02/2015)
		site.	, ,
	Danga / Fraguenay		Generate using Fluke
	Range / Frequency	10 Hz	5522A based on
	33 mV to 330 mV	to	EURAMET cg-15,
	330 mV to 3.3 V	45 Hz	Version 3 (02/2015)
	3.3 V to 33 V	0.33	Version 3 (02/2013)
	33 V to 330 V	mV / V	
	330 V to 750 V	0.32	
		mV / V	
		0.34	
		mV / V	
		-	

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Instrument Calibrated/Measurement Parameter	Range	Calibration and Measurement Capability Expressed as an Uncertainty (±)*	Remarks
Measuring Instrument (dc Current)	0 mA to 330 mA 330 mA to 3.3 mA 3.3 mA to 330 mA 33 mA to 330 mA 330 mA to 1.1 A 1.1 A to 3 A 3 A to 10 A	0.17 nA / A + 23 nA 0.11 mA / A + 57 mA 0.11 mA / A + 0.29 mA 0.11 mA / A + 2.9 mA 0.23 mA / A + 47 mA 0.43 mA / A + 46 mA 0.57 mA / A + 0.57 mA Note: Apply EOS for onsite.	Generate using Fluke 5522A based on EURAMET cg-15, Version 3 (02/2015)
Measuring Instrument (ac Current)	33 mA to 10 A	See Matrix E Note: Apply EOS for onsite.	Generate using Fluke 5522A based on EURAMET cg-15, Version 3 (02/2015)
	Range / Frequency 33 mA to 330 mA 330 mA to 3.3 mA 3.3 mA to 33 mA 330 mA to 1.1 A 1.1 A to 3 A 3 A to 10 A	10 Hz to 20 Hz	Generate using Fluke 5522A based on EURAMET cg-15, Version 3 (02/2015)

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SCOPE OF CALIBRATION: PRESSURE

Instrument	Range	Calibration and	Remarks
Calibrated/Measurement		Measurement	
Parameter		Capability	
		Expressed as an	
		Uncertainty (+)*	

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SCOPE OF CALIBRATION: TEMPERATURE

Instrument	Range	Calibration and	Remarks
Calibrated/Measurement		Measurement	
Parameter		Capability	
		Expressed as an	
		Uncertainty (±)*	